



2872

PATENT  
Docket No.: 176/60930

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : David P. Biss, Thomas G. Brown, and  
Kathleen S. Youngworth

Examiner:  
R. D. Shafer

Serial No. : 09/759,913

Art Unit:  
2872

Cnfrm. No. : 2814

Filed : January 12, 2001

For : AN APPARATUS FOR PRODUCTION OF  
INHOMOGENEOUSLY POLARIZED  
OPTICAL BEAMS FOR USE IN  
ILLUMINATION AND A METHOD  
THEREOF

INFORMATION DISCLOSURE STATEMENT  
UNDER 37 CFR §§ 1.97-1.98

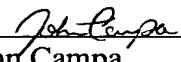
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Pursuant to 37 CFR §§ 1.97-1.98, applicants hereby bring to the attention of the  
United States Patent and Trademark Office, the enclosed references listed on the attached  
PTO-1449 form.


Respectfully submitted,

Date: May 5, 2003

  
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R683063.1

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I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450, on the date below.	
Date	5/5/03
	 Sherri A. Moscato

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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT MAY 08 2003 (use several sheets if necessary) (PTO-1449)	ATTY. DOCKET NO. 176/60930	SERIAL NO. 09/759,913
	APPLICANT David P. Biss, Thomas G. Brown, and Kathleen S. Youngworth	
	FILING DATE January 12, 2001	GROUP ART UNIT 2872

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPRO- PRIATE

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANS- LATION IF APPRO- PRIATE

## OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, Etc.)

		1	K. S. Youngworth et al., "Inhomogeneous Polarization in Scanning Optical Microscopy," <u>Proceeding of the SPIE</u> , 3919:75-85 (2000).
EXAMINER			DATE CONSIDERED
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			

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